PCN Number:		20	1510	1009001			PCN D	PCN Date: 10/16/201		
Title:Qualification of MIH8 for select					Options (MFAB for e)	selec	t LM3640	5YFQ	Devices and	
Customer Contact:				<u>PCN</u>	Manager Dept: 0			Qual	ity Services	
Proposed 1 st Ship Date		•	01/1	.6/2015 Estimated Sample Availability:				te provided at mple request.		
Change Type:										
Assembly Site				Assembly Process		Assembly Materials				
Design				Electrical Specification		Mec	Mechanical Specification			
	Test S	ite			Packing/Shipping/Labeling		Test	Test Process		
Wafer Bump Site				Wafer Bump Material		Wafe	Wafer Bump Process			
Wafer Fab Site				Wafer Fab Materials		Wafer Fab Process				
					Part number change					
PCN Details										

Description of Change:

This change notification is to announce the qualification of additional fab site options (MFAB for select LM3646YFQ devices and MIH8 for the TPS51631RSM device). These devices are listed in the Product Affected Section.

Group 1: LM3646YFQ (adding MFAB) Group 2: TPS51631RSM (adding MIH8)

	Current				Additional		
Device Group	Current Fab Site	Process	Wafer Diameter	Additional Fab Site	Process	Wafer Diameter	
1	Aizu	CMOS7	200 mm	MFAB	CMOS7	200mm	
2	RFAB	LBC7	300mm	MIH8	LBC7	200 mm	

Reason for Change: Continuity of Supply

Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative): None

Changes to product identification resulting from this PCN:

III	

Current			
Chip Sites	Chip site code	Chip country code	Chip Site City
	(20L)	(21L)	
AIZU	CU2	JPN	Aizuwakamatsu-shi
RFAB	RFB	USA	Richardson
New		•	

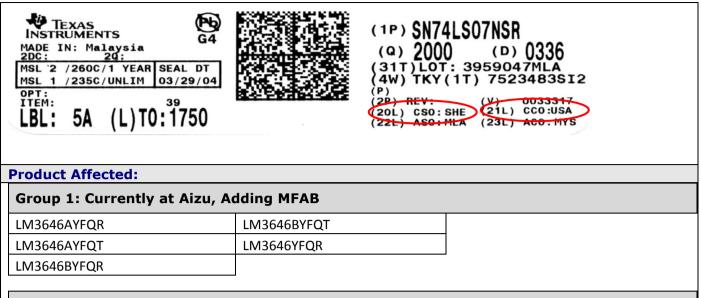
Chip country code

Chip Site	Chip site code
	(20L)

	(20L)	(21L)	
MAINEFAB	CUA	USA	South Portland
MIH8	MH8	JPN	Ibaraki
	•		

Sample product shipping label (not actual product label)

Chip Site City



Group 2: TPS51631RSM Currently at RFAB Adding MIH8

TPS51631RSMR

TPS51631RSMT

Group 1: Qualification Report

LM3646A PRODUCT QUALIFICATION - CMOS7 at MFAB Approved 10/05/2015

Product Attributes

Attributes	QBS Product: LM3564A1TMX
Assembly Site	TIEM-MALACCA
Package Family	DSBGA
Flammability Rating	UL 94 V-0
Wafer Fab Site	MFAB
Wafer Fab Process	CMOS7 5V

- QBS: Qual By Similarity

- Qual Device LM3646YFQ is qualified at LEVEL1-260C

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Test Name / Condition	Duration	QBS Product: LM3564A1TMX
PreCon Level 1	Visual Post	3/462/0
Biased HAST, 130C/85%RH	96 Hours	3/231/0
Temperature Cycle, -65/150C	500 Cycles	3/231/0
High Temp Storage Bake 150C	1000 Hours	3/231/0
Life Test, 125C	1000 Hours	3/231/0
ESD - HBM	2000 V	3/9/0
ESD - CDM	750 V	3/9/0
Latch-up	25C	3/18/0
Latch-up	85C	3/18/0

- Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV : 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV : 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47 : -55C/125C/700 Cycles and -65C/150C/500 Cycles Quality and Environmental data is available at TI's external Web site: http://www.ti.com/ Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

Group 2: Qualification Report

TPS51631RSMR/T Miho die in Clark Approve Date 9/17/2015

Product Attributes

Attributes	Qual Device: TPS51631RSM	QBS Product Reference: TPS51622RSM	QBS Product Reference: TPS51631RSM	QBS Process Reference: TPS62110RSA
Assembly Site	CLARK-AT	CARZ	CLARK-AT	CAR
Flammability Rating	UL 94 V-0	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	MIHO	MIHO	RFAB	MIHO
Wafer Process	LBC7	LBC7	LBC7	LBC7

- QBS: Qual By Similarity

- Qual Device TPS51631RSM is qualified at LEVEL2-260CG

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Test Name / Condition	Duration	Qual Device: TPS51631RSM	QBS Product Reference: TPS51622RSM	QBS Product Reference: TPS51631RSM	QBS Process Reference: TPS62110RSA
Autoclave 121C	96 Hours	-	1/77/0	-	3/231/0
Electrical Characterization.	Per Datasheet Parameters	Pass	Pass	Pass	-
Biased HAST, 130C/85%RH	96 Hours	-	-	-	3/231/0
ESD - HBM	2500 V	1/3/0	1/3/0	-	-
ESD - CDM	1500 V	1/3/0	1/3/0	-	-
HTOL/Life Test, 125C	1000 Hours	-	-	1/77/0	-
HTOL/Life Test, 140C	480 Hours	-	-	-	3/231/0
High Temp. Storage Bake, 170C	420 Hours	-	-	1/77/0	3/231/0
Latch-up	(per JESD78)	1/6/0	1/6/0	1/6/0	3/15/0
Temperature Cycle, - 65/150C	500 Cycles	-	1/77/0	1/77/0	3/231/0

For questions regarding this notice, e-mails can be sent to the regional contacts shown below, or you can contact your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
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